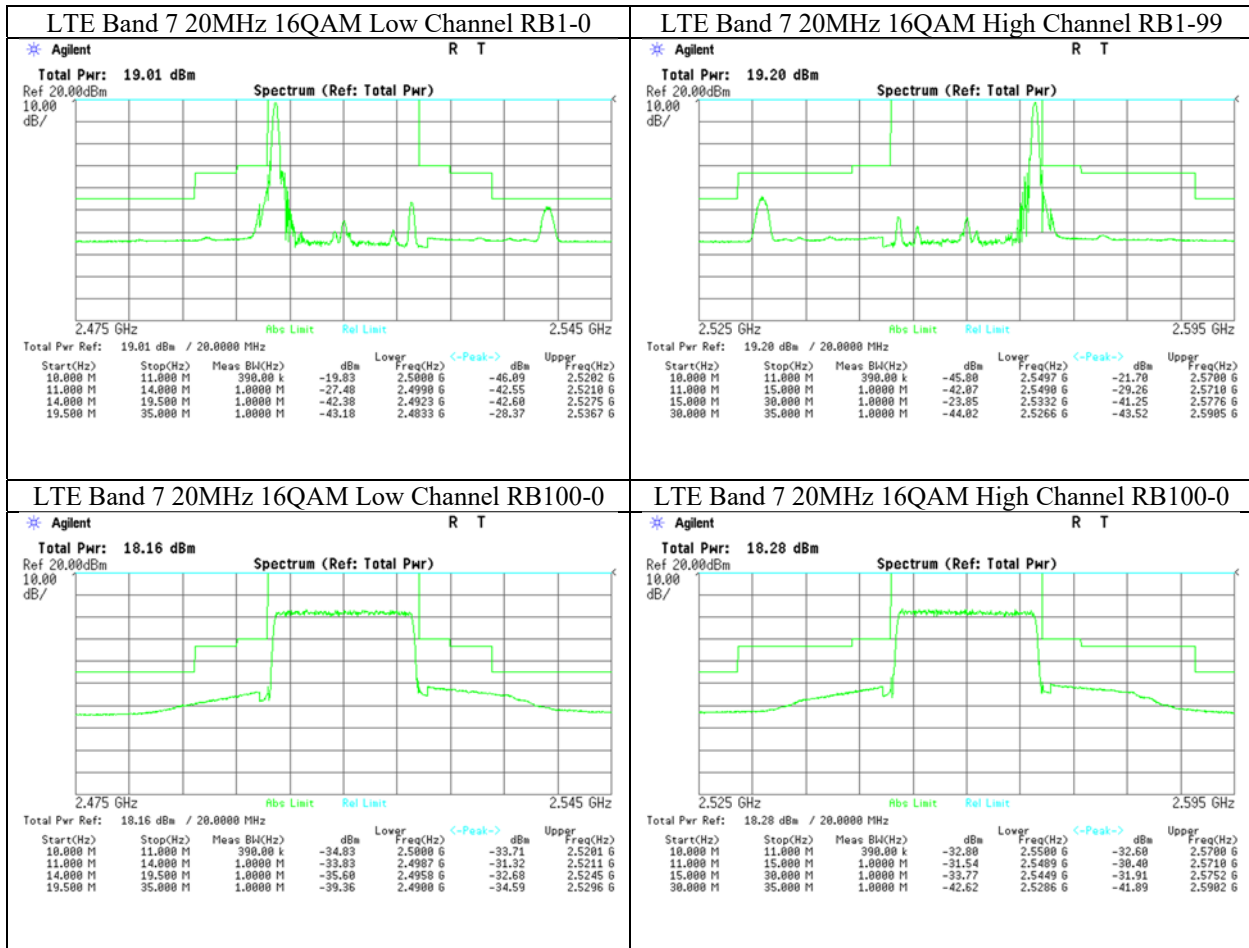


Band Edge (Conducted)

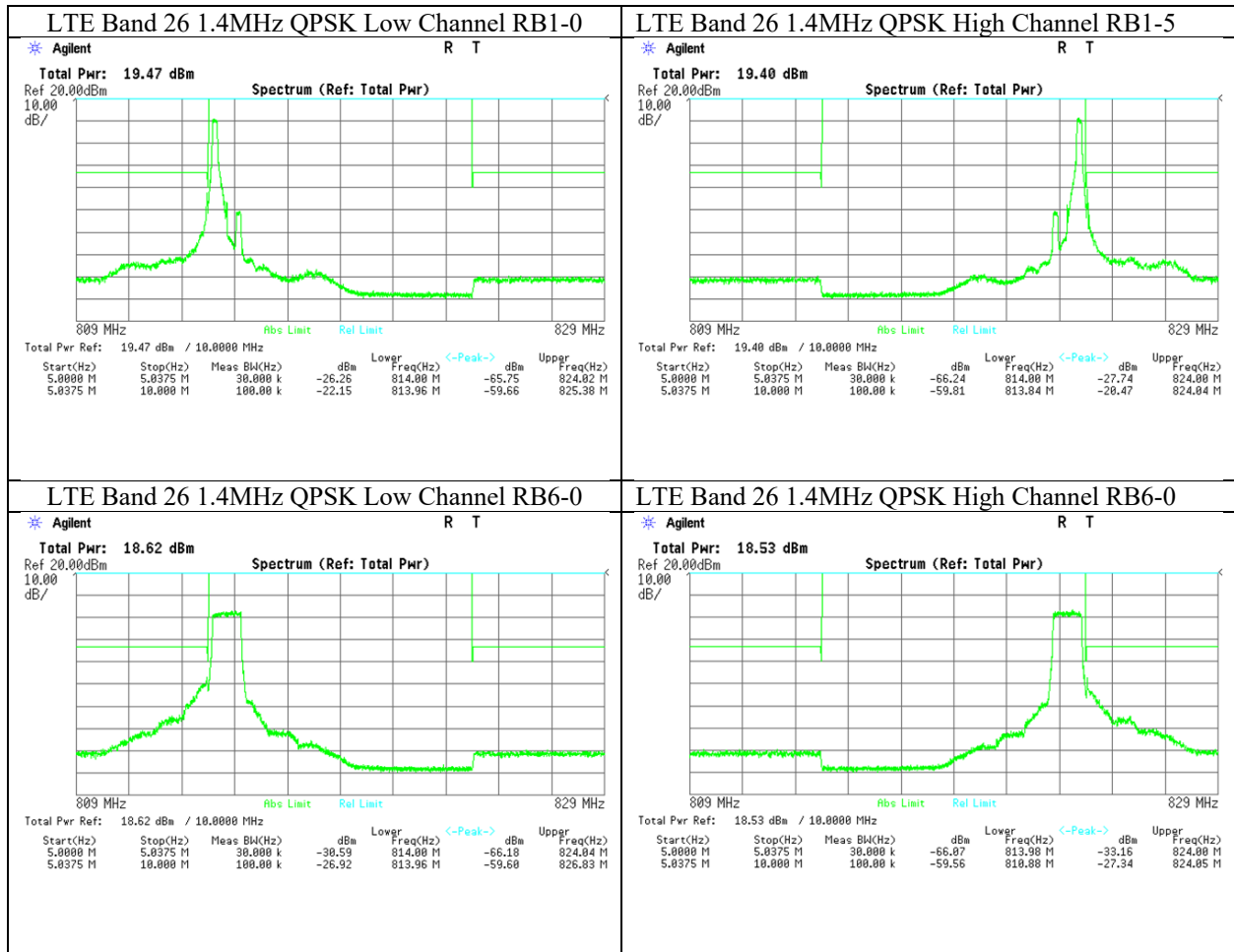
Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 19, 2020
Temperature / Humidity 22 deg. C / 46 % RH
Engineer Tomohisa Nakagawa
Mode LTE



Band Edge (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 20, 2020
 Temperature / Humidity 22 deg. C / 45 % RH
 Engineer Tomohisa Nakagawa

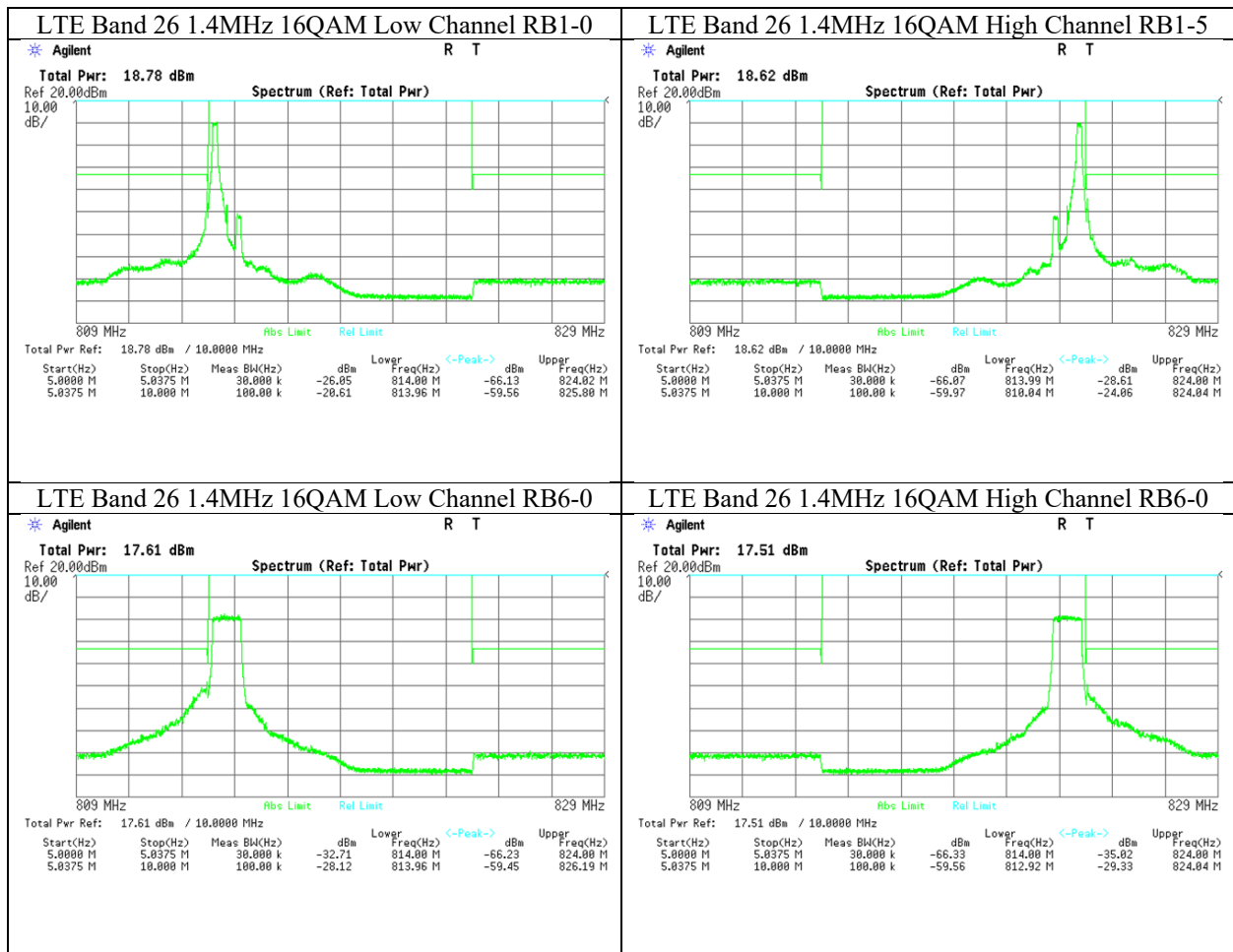
Mode LTE



Band Edge (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 20, 2020
Temperature / Humidity 22 deg. C / 45 % RH
Engineer Tomohisa Nakagawa

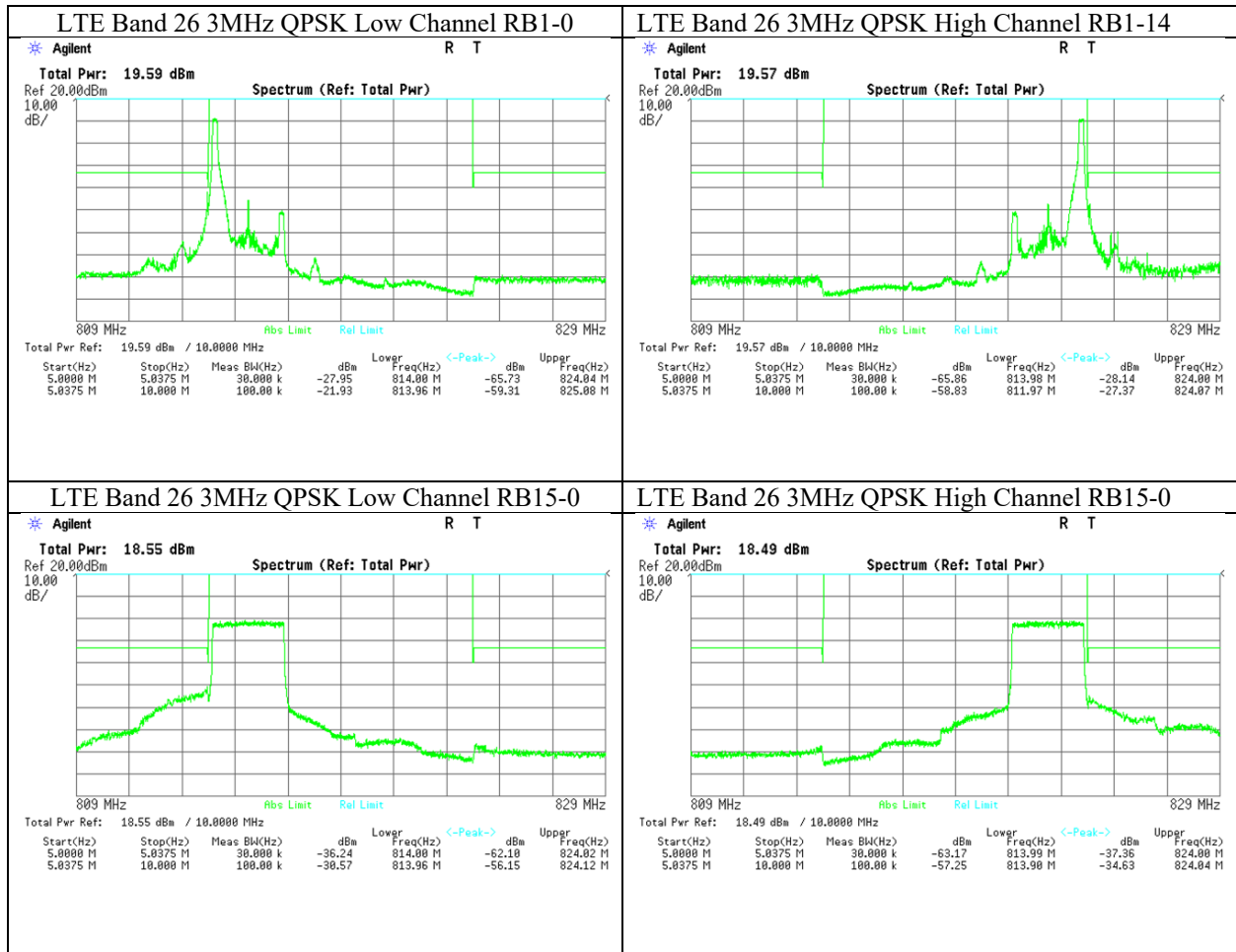
Mode LTE



Band Edge (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 20, 2020
Temperature / Humidity 22 deg. C / 45 % RH
Engineer Tomohisa Nakagawa

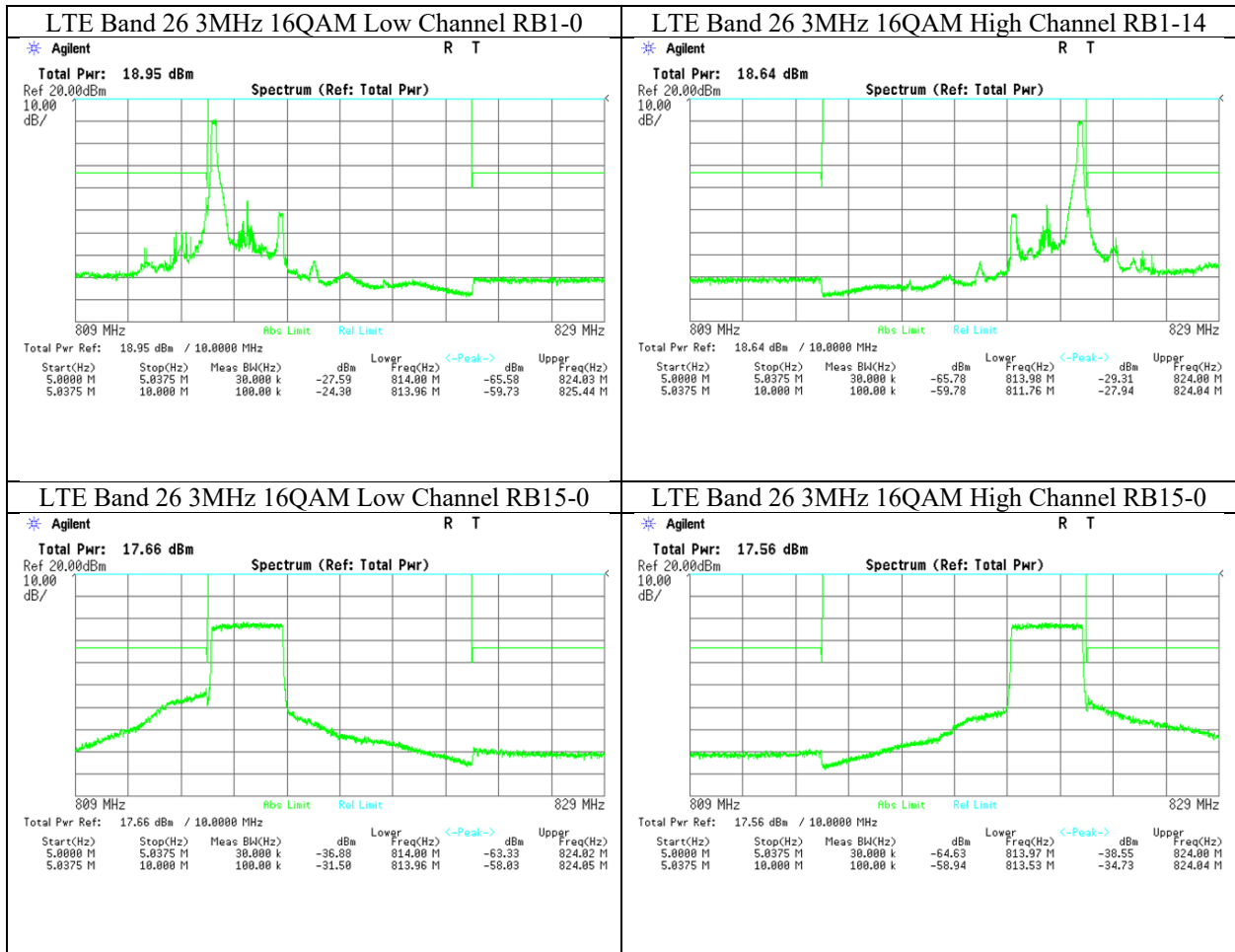
Mode LTE



Band Edge (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 20, 2020
 Temperature / Humidity 22 deg. C / 45 % RH
 Engineer Tomohisa Nakagawa

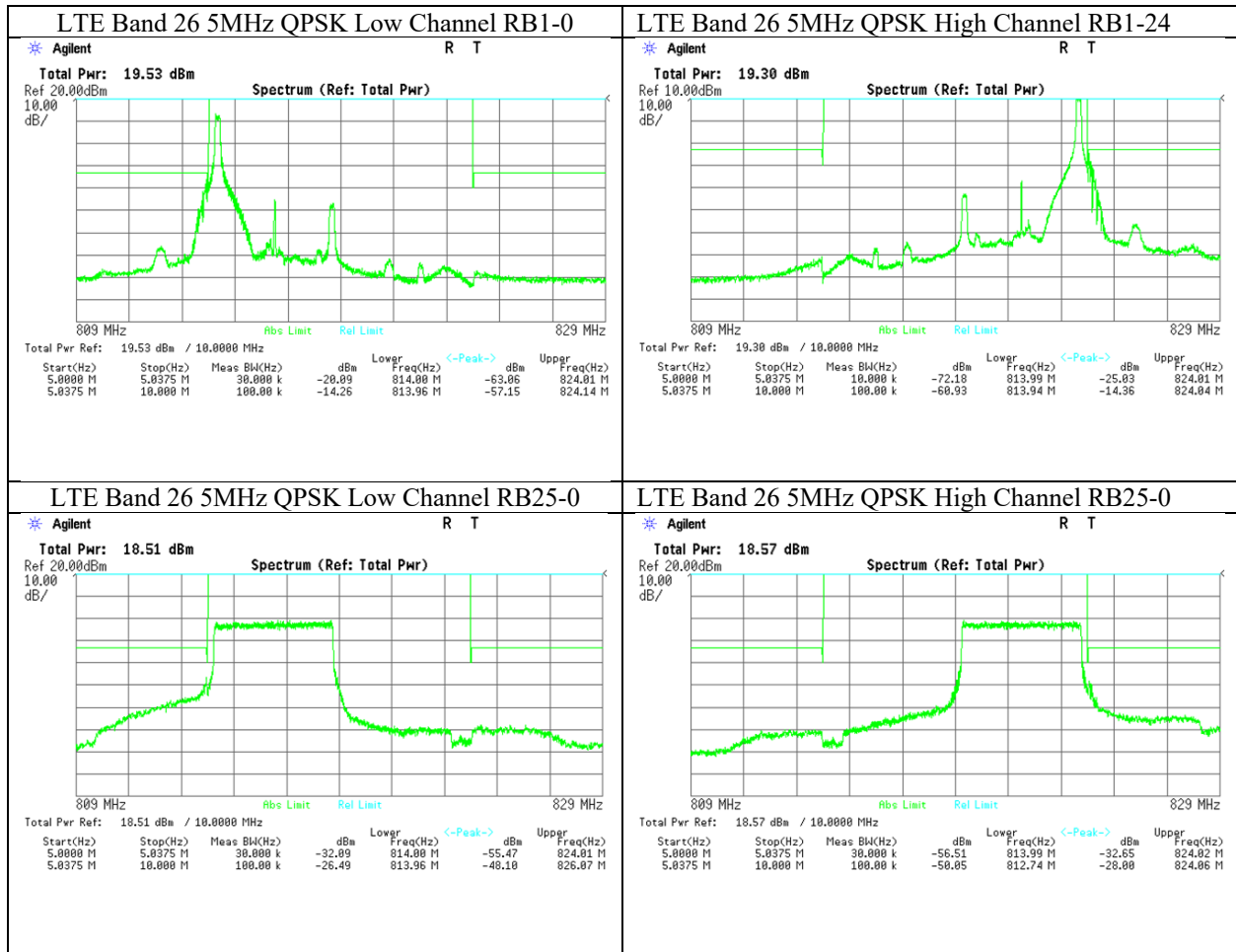
Mode LTE



Band Edge (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 20, 2020
Temperature / Humidity 22 deg. C / 45 % RH
Engineer Tomohisa Nakagawa

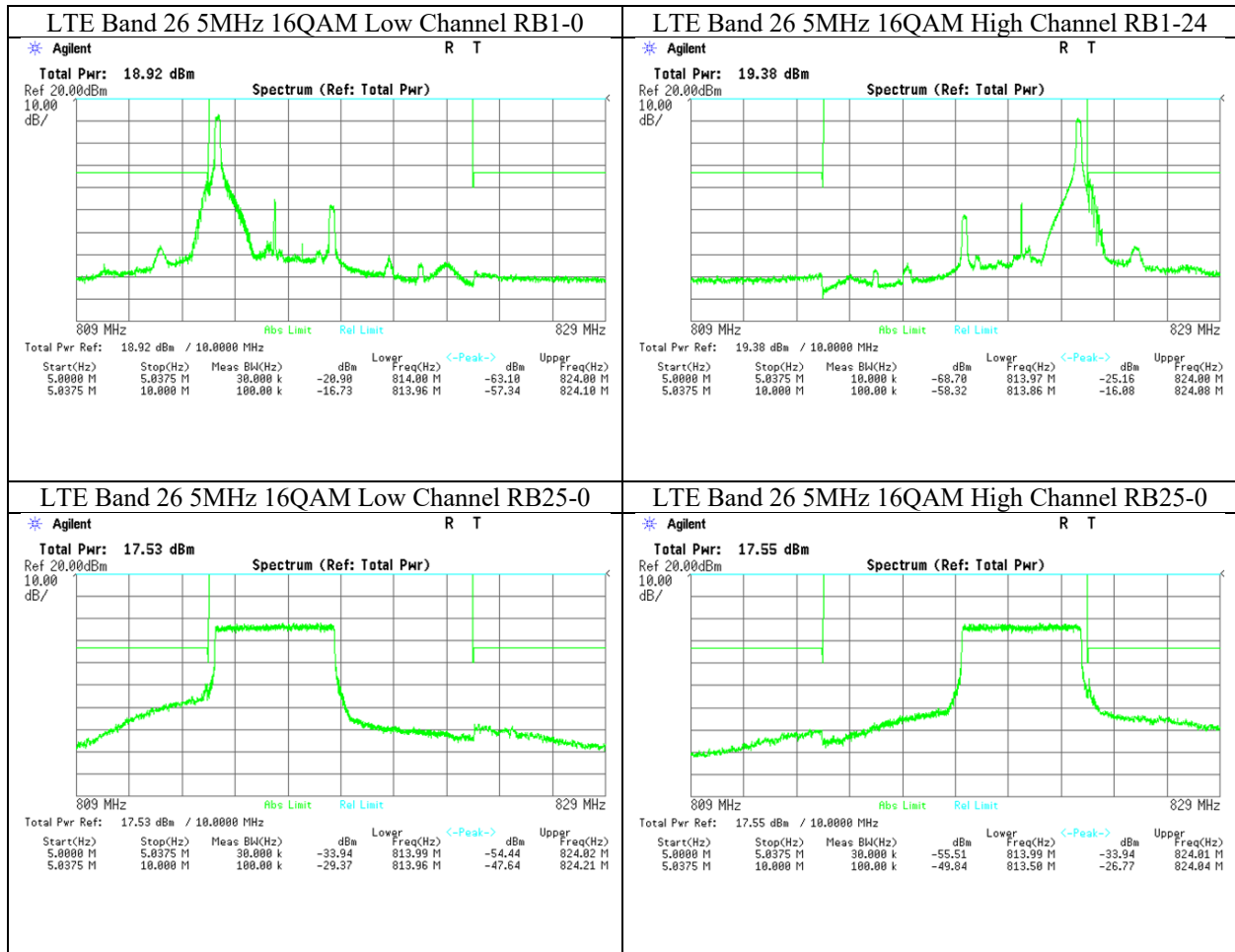
Mode LTE



Band Edge (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 20, 2020
Temperature / Humidity 22 deg. C / 45 % RH
Engineer Tomohisa Nakagawa

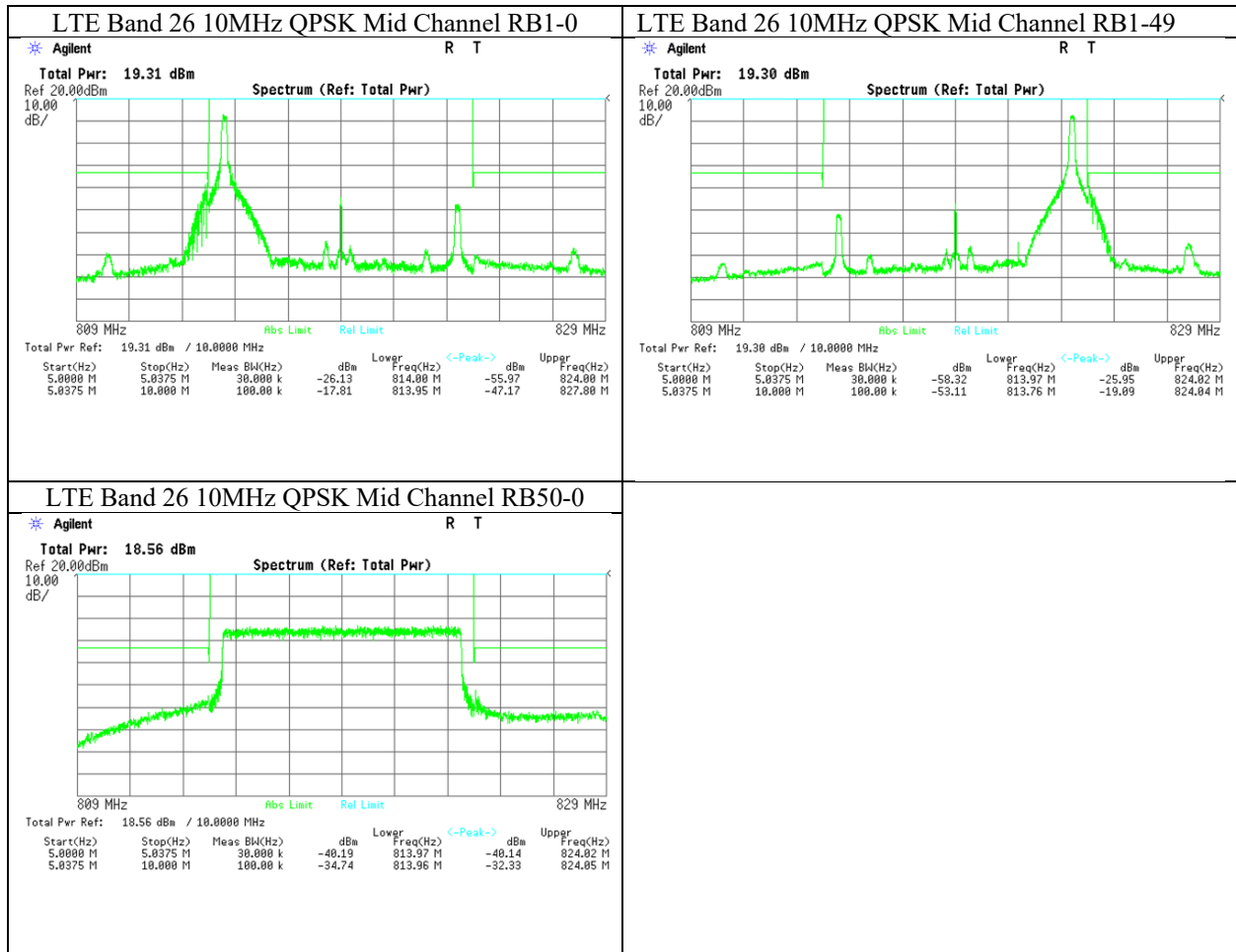
Mode LTE



Band Edge (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 20, 2020
 Temperature / Humidity 22 deg. C / 45 % RH
 Engineer Tomohisa Nakagawa

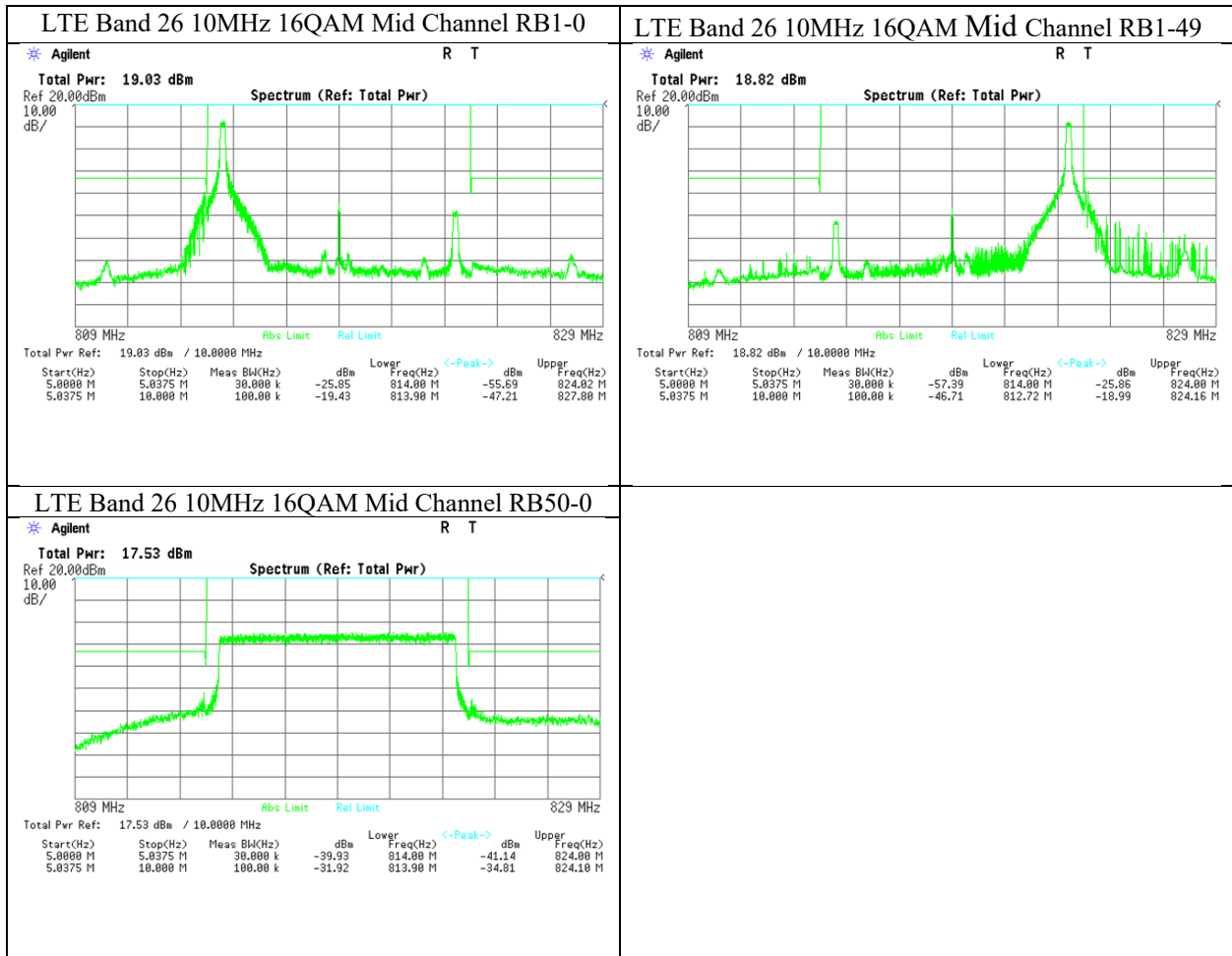
Mode LTE



Band Edge (Conducted)

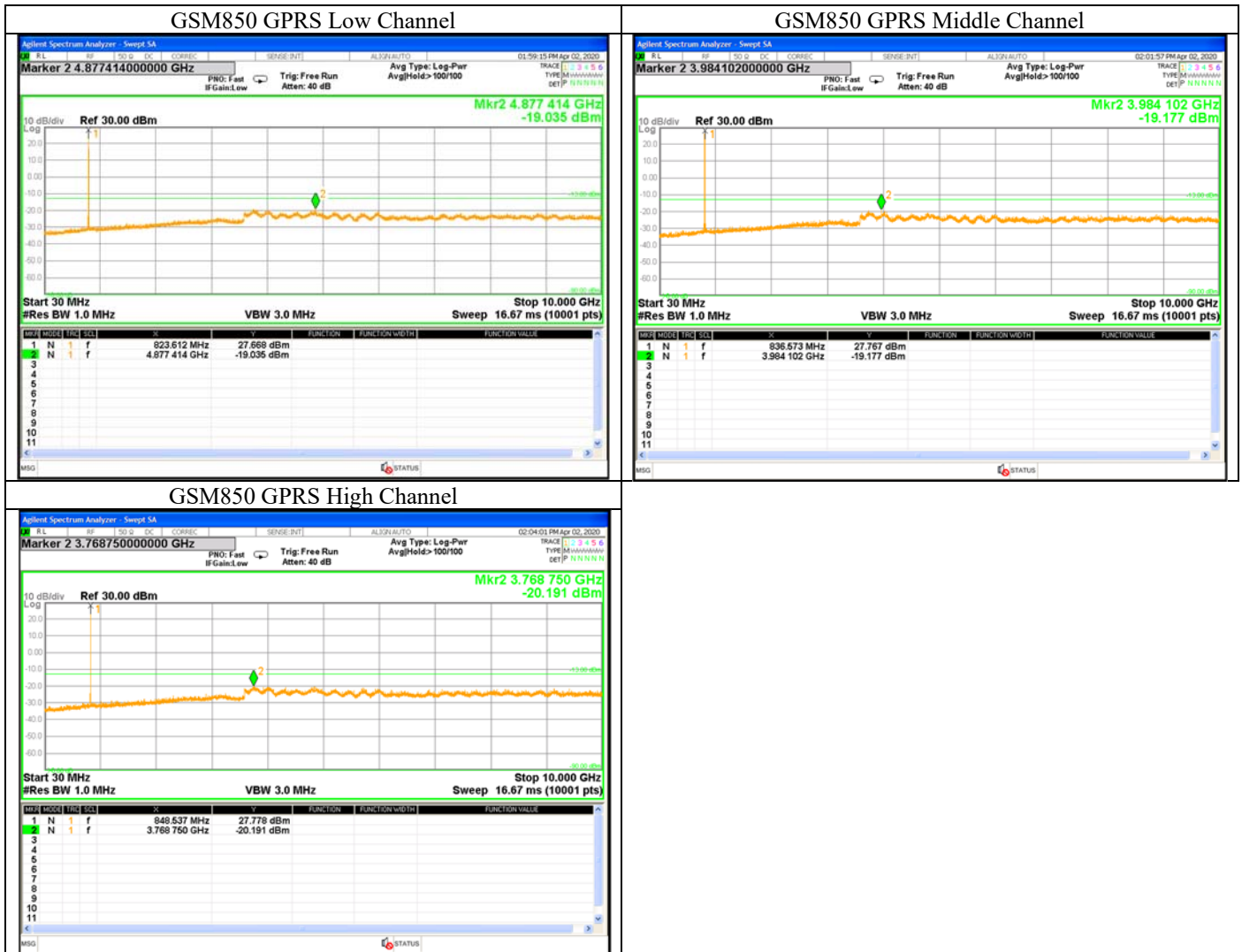
Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 20, 2020
 Temperature / Humidity 22 deg. C / 45 % RH
 Engineer Tomohisa Nakagawa

Mode LTE



Spurious Emission (Conducted)

Report No.	13274888H
Test place	Ise EMC Lab.
Shielded Room	No.5
Date	April 2, 2020
Temperature / Humidity	23 deg. C / 40 % RH
Engineer	Yutaka Yoshida
Mode	GSM



Spurious Emission (Conducted)

Report No.	13274888H
Test place	Ise EMC Lab.
Shielded Room	No.5
Date	April 2, 2020
Temperature / Humidity	23 deg. C / 40 % RH
Engineer	Yutaka Yoshida
Mode	GSM



Spurious Emission (Conducted)

Report No.	13274888H
Test place	Ise EMC Lab.
Shielded Room	No.5
Date	April 2, 2020
Temperature / Humidity	22 deg. C / 40 % RH
Engineer	Yutaka Yoshida
Mode	GSM



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Ise EMC Lab.

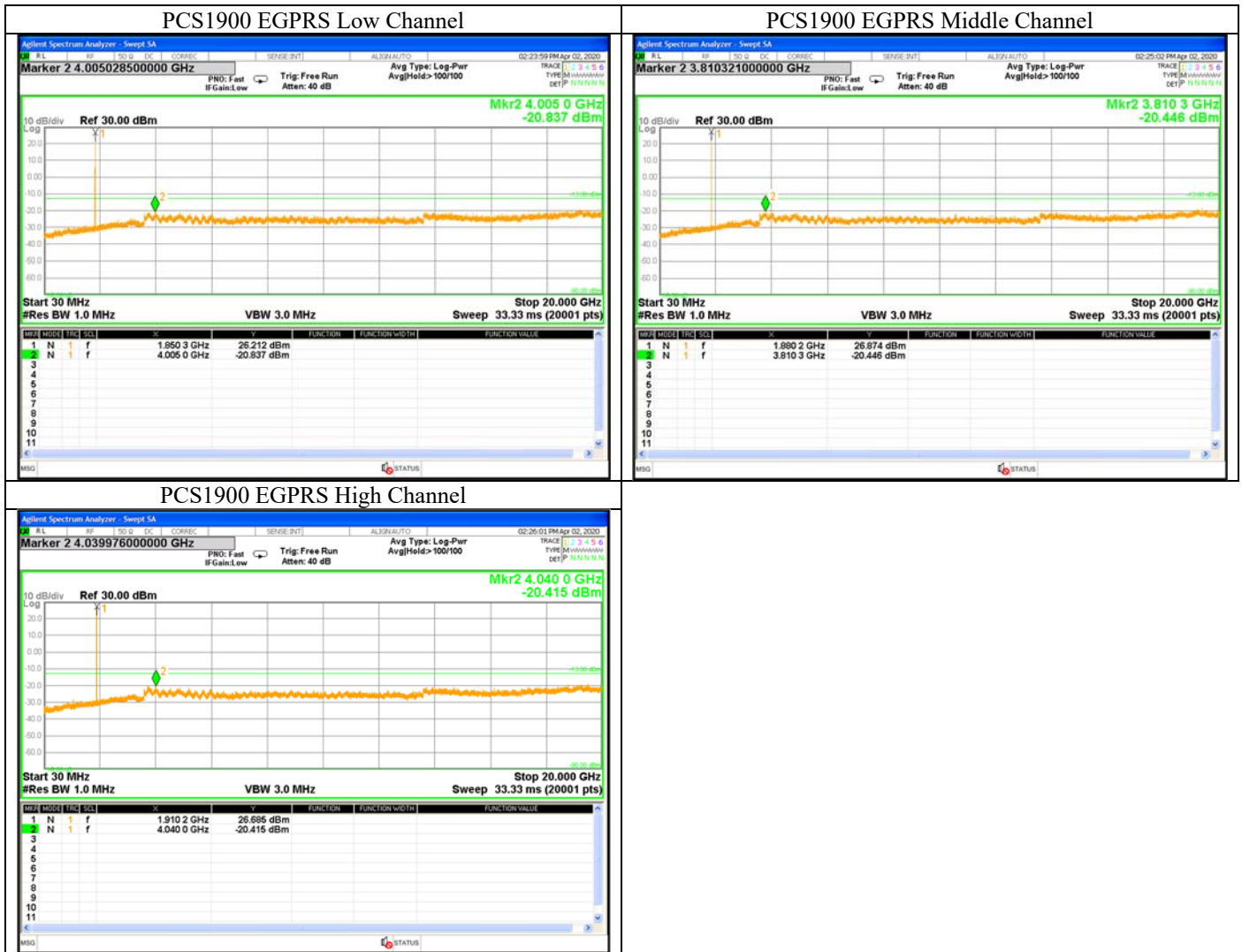
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8999

Facsimile : +81 596 24 8124

Spurious Emission (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.5
Date April 2, 2020
Temperature / Humidity 23 deg. C / 40 % RH
Engineer Yutaka Yoshida
Mode GSM



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Ise EMC Lab.

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Facsimile : +81 596 24 8124

Spurious Emission (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 16, 2020
 Temperature / Humidity 22 deg. C / 45 % RH
 Engineer Tomohisa Nakagawa
 Mode W-CDMA



Spurious Emission (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 17, 2020
 Temperature / Humidity 22 deg. C / 43 % RH
 Engineer Tomohisa Nakagawa
 Mode W-CDMA



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Spurious Emission (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 16, 2020
Temperature / Humidity 22 deg. C / 45 % RH
Engineer Tomohisa Nakagawa
Mode W-CDMA



Spurious Emission (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 17, 2020
Temperature / Humidity 22 deg. C / 43 % RH
Engineer Tomohisa Nakagawa
Mode W-CDMA



Spurious Emission (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 8, 2020
 Temperature / Humidity 23 deg. C / 54 % RH
 Engineer Yutaka Yoshida
 Mode LTE



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Ise EMC Lab.

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Spurious Emission (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 8, 2020
 Temperature / Humidity 23 deg. C / 54 % RH
 Engineer Yutaka Yoshida
 Mode LTE



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Spurious Emission (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 8, 2020
 Temperature / Humidity 23 deg. C / 54 % RH
 Engineer Yutaka Yoshida
 Mode LTE



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Spurious Emission (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 8, 2020
Temperature / Humidity 23 deg. C / 54 % RH
Engineer Yutaka Yoshida
Mode LTE



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Spurious Emission (Conducted)

Report No.	13274888H	No.6
Test place	Ise EMC Lab.	March 6, 2020
Shielded Room	No.6	22 deg. C / 44 % RH
Date	January 8, 2020	Yutaka Yoshida
Temperature / Humidity	23 deg. C / 54 % RH	
Engineer	Yutaka Yoshida	
Mode	LTE	



Spurious Emission (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 8, 2020
 Temperature / Humidity 23 deg. C / 54 % RH
 Engineer Yutaka Yoshida
 Mode LTE



Spurious Emission (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 8, 2020
Temperature / Humidity 23 deg. C / 54 % RH
Engineer Yutaka Yoshida
Mode LTE



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Ise EMC Lab.

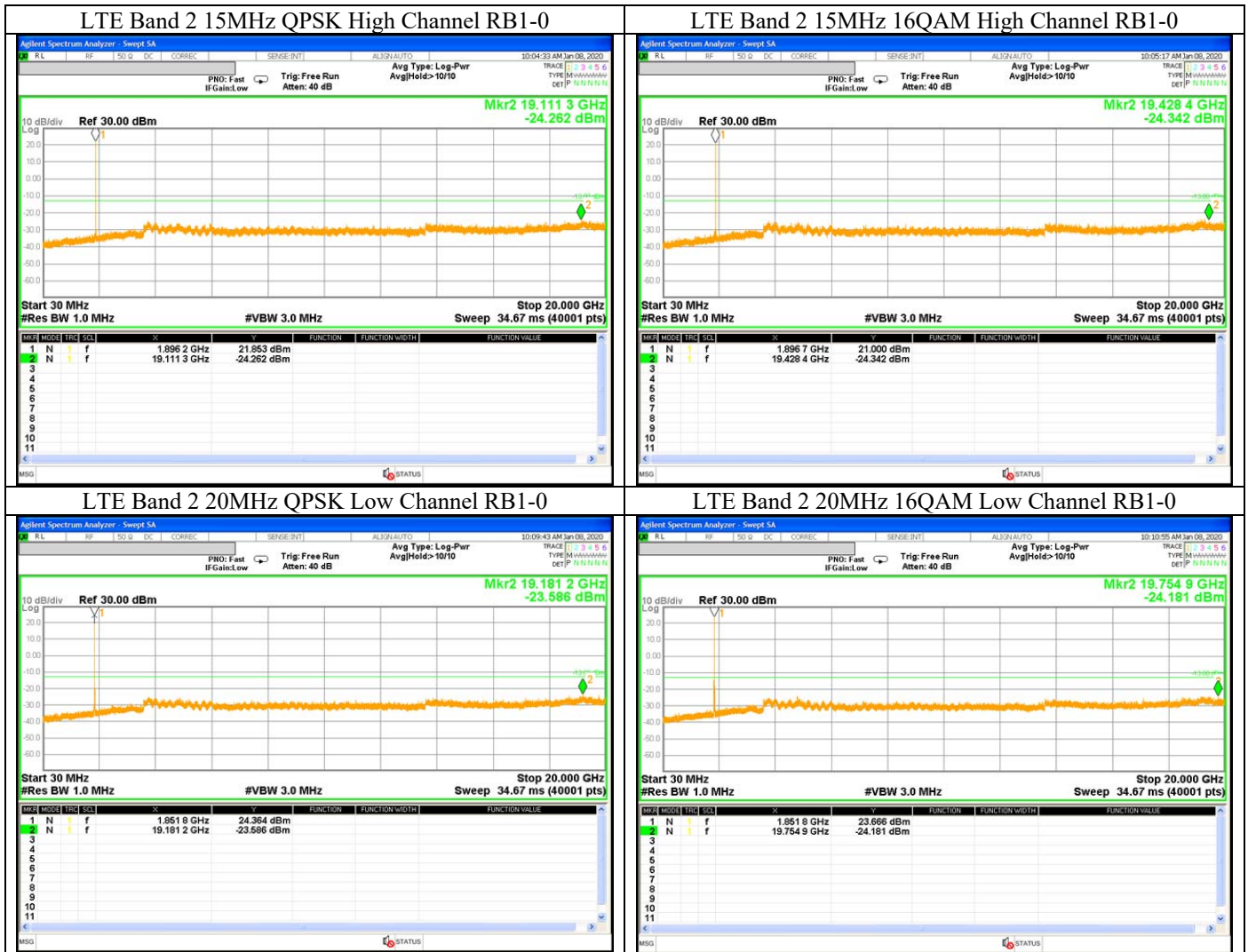
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

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Facsimile : +81 596 24 8124

Spurious Emission (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 8, 2020
Temperature / Humidity 23 deg. C / 54 % RH
Engineer Yutaka Yoshida
Mode LTE



Spurious Emission (Conducted)

Report No. 13274888H
 Test place Ise EMC Lab.
 Shielded Room No.6
 Date January 8, 2020
 Temperature / Humidity 23 deg. C / 54 % RH
 Engineer Yutaka Yoshida
 Mode LTE



UL Japan, Inc.

Ise EMC Lab.

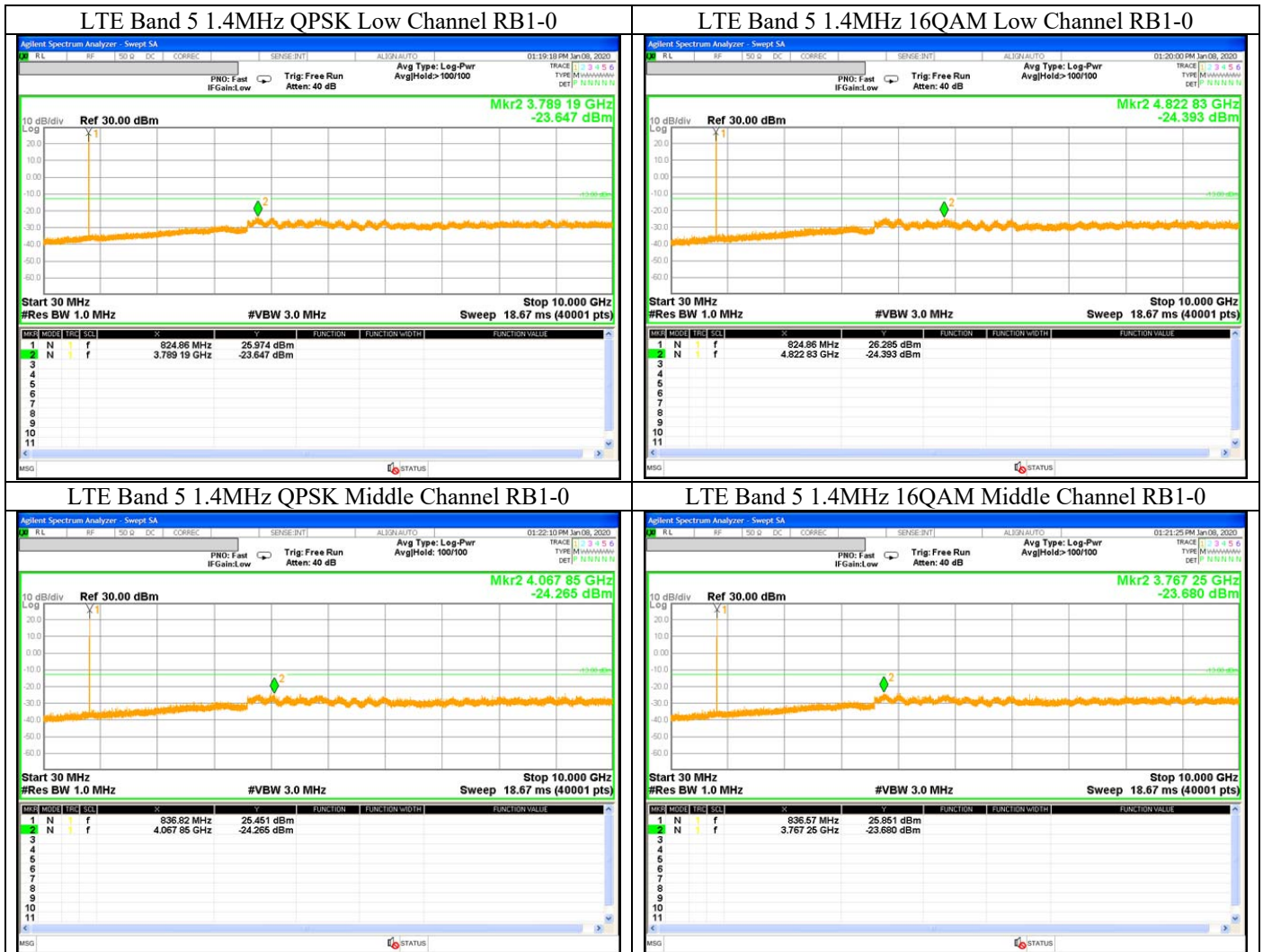
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Spurious Emission (Conducted)

Report No. 13274888H
Test place Ise EMC Lab.
Shielded Room No.6
Date January 8, 2020
Temperature / Humidity 23 deg. C / 54 % RH
Engineer Yutaka Yoshida
Mode LTE



UL Japan, Inc.

Ise EMC Lab.

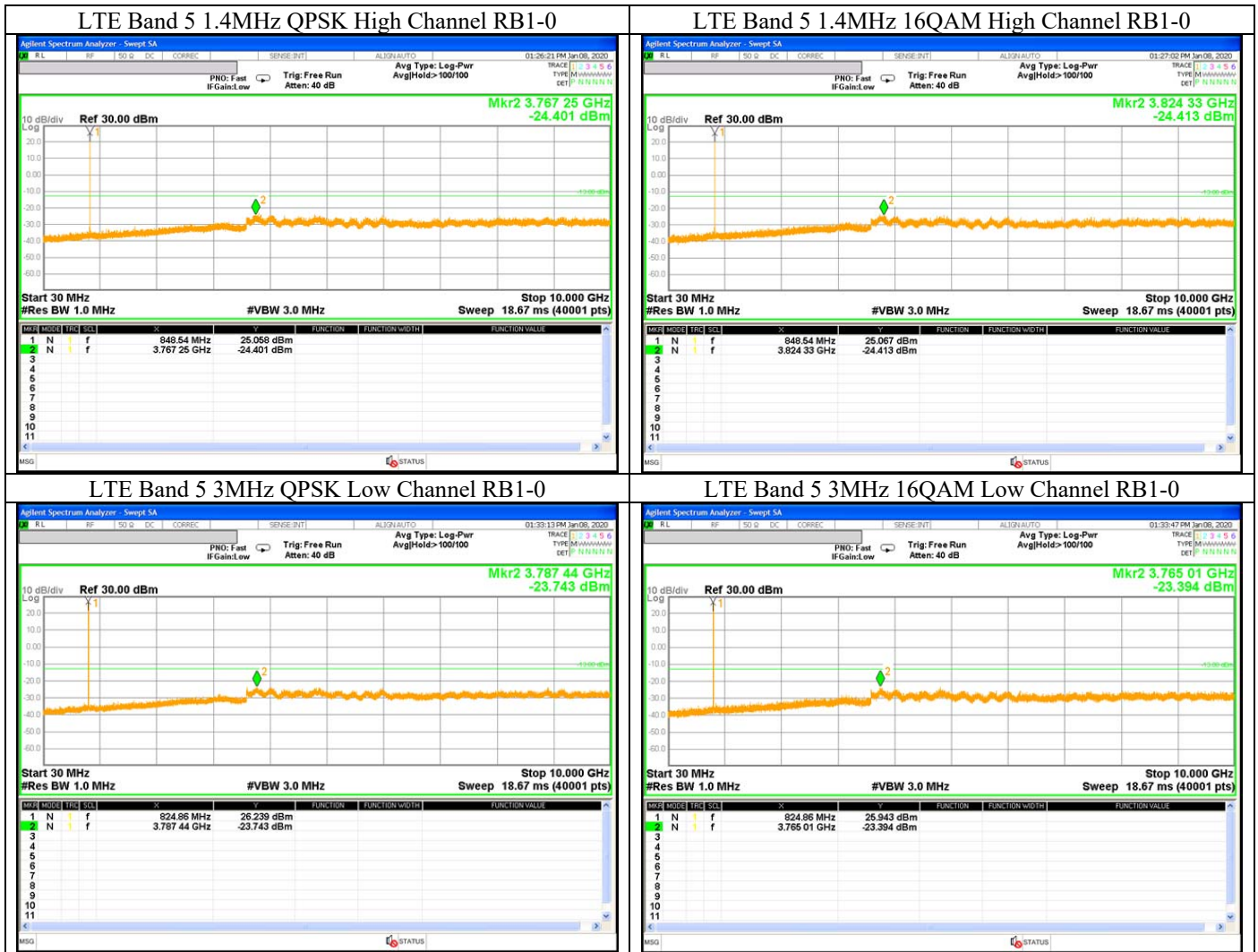
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Test place Ise EMC Lab.
Shielded Room No.6
Date January 8, 2020
Temperature / Humidity 23 deg. C / 54 % RH
Engineer Yutaka Yoshida
Mode LTE



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